## AMENDMENTS TO THE CLAIMS

- 1-9. (Cancelled)
- 10. (Original) A method for fabricating an a-C:H gate ISFET device, comprising steps of:

providing a semiconductor substrate;

forming an virtual gate on the semiconductor substrate to define the gate area of the ISFET;

forming a source/drain in the semiconductor substrate beside the virtual gate;

removing the virtual gate;

forming an a-C:H gate in the gate area to form a ISFET by PE-LPCVD.

11. (Original) The method as claimed in claim 10, wherein forming the virtual gate to define the gate area of the ISFET further comprises:

rinsing the semiconductor substrate;

forming a pad oxide layer on the semiconductor substrate; and removing a portion of the oxide layer to form a virtual gate to define the gate area.

12. (Original) The method as claimed in claim 11, wherein the PE-LPCVD is performed under conditions of:

base pressure at least 10<sup>-6</sup> torr;

temperature of the semiconductor substrate between  $140^{\circ}\text{C}$  and  $160^{\circ}\text{C}$ ;

a mixing gas comprising methane and hydrogen at flow ratio between 6 to 10 SCCM;

the process pressure between 0.08 and 0.1 torr; and a RF power between 145W and 160W.

- 13. (Original) The method as claimed in claim 10, further comprising a step of forming a gate oxide layer below the a-C:H gate in the gate area.
- 14. (Original) The method as claimed in claim 10, wherein forming the source/drain beside the virtual gate further comprises doping the semiconductor substrate by the virtual gate as a mask to form a source/drain.
- 15. (Original) The method as claimed in claim 12, wherein the ratio of the methane and hydrogen, in the mixing gas, is 30 to 70.
- 16. (Original) The method as claimed in claim 12, wherein the temperature of the semiconductor substrate is 150°C.

- 17. (Currently Amended) The method as claimed in claim  $\pm \underline{12}$ , wherein the flow ratio of the mixing gas is 8SCCM.
- 18. (Currently Amended) The method as claimed in claim  $\pm 12$ , wherein the pressure of the mixing gas of methane and hydrogen is 0.09 torr.
- 19. (Currently Amended) The method as claimed in claim  $\pm \underline{12}$ , wherein the RF power is 150W.

20-49. (Cancelled)